# Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators 


#### Abstract

General Description The MAX9972 four-channel, ultra-low-power, pin-electronics IC includes, for each channel, a three-level pin driver, a window comparator, a passive load, and force-and-sense Kelvin-switched parametric measurement unit (PMU) connections. The driver features a -2.2 V to +5.2 V voltage range, includes high-impedance and active-termination (3rd-level drive) modes, and is highly linear even at low voltage swings. The window comparator features 500 MHz equivalent input bandwidth and programmable output voltage levels. The passive load provides pullup and pulldown voltages to the device-under-test (DUT). Low-leakage, high-impedance, and terminate controls are operational configurations that are programmed through a 3-wire, low-voltage, CMOS-compatible serial interface. High-speed PMU switching is realized through dedicated digital control inputs. This device is available in an $80-\mathrm{pin}, 12 \mathrm{~mm} \times 12 \mathrm{~mm}$ body, 1.0 mm pitch TQFP with an exposed $6 \mathrm{~mm} \times 6 \mathrm{~mm}$ die pad on the bottom of the package for efficient heat removal. The MAX9972 is specified to operate over the $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ commercial temperature range, and features a die temperature monitor output.


Applications
NAND Flash Testers
DRAM Probe Testers
Low-Cost Mixed-Signal/System-on-Chip (SoC)
Testers
Active Burn-In Systems
Structural Testers

| - Small Footprint-Four Channels in 0.3in ${ }^{\mathbf{2}}$ |  |  |  |
| :---: | :---: | :---: | :---: |
| - Low-Power Dissipation: 325mW/Channel (typ) |  |  |  |
| - High Speed: 300Mbps at 3VP-P |  |  |  |
| - -2.2V to +5.2V Operating Range |  |  |  |
| - Active Termination (3rd-Level Drive) |  |  |  |
| - Integrated PMU Switches |  |  |  |
| - Passive Load |  |  |  |
| - Low-Leak Mode: 20nA (max) |  |  |  |
| - Low Gain and Offset Error |  |  |  |
| Ordering Information |  |  |  |
| PART | TEMP RANGE | PINPACKAGE | HEAT <br> EXTRACTION |
| MAX9972ACCS+ | $\begin{aligned} & 0^{\circ} \mathrm{C} \text { to } \\ & +70^{\circ} \mathrm{C} \end{aligned}$ | 80 TQFP-EP* | Bottom |

+Denotes a lead(Pb)-free/RoHs-compliant package.
*EP = Exposed pad.

Pin Configuration appears at end of data sheet.

## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators

## ABSOLUTE MAXIMUM RATINGS




Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## ELECTRICAL CHARACTERISTICS

$\left(\mathrm{V}_{\mathrm{DD}}=+8 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=-5 \mathrm{~V}, \mathrm{~V}_{\mathrm{L}}=+3 \mathrm{~V}, \mathrm{~V}_{\mathrm{COMPHI}}=+1 \mathrm{~V}, \mathrm{~V}_{\mathrm{COMPLO}}=0 \mathrm{~V}, \mathrm{~V}_{\text {LDV }}=0 \mathrm{~V}\right.$, LOAD EN LOW $=\mathrm{LOAD} \mathrm{EN} \mathrm{HIGH}=0$, $\mathrm{T}_{J}=+75^{\circ} \mathrm{C}$. All temperature coefficients measured at $\mathrm{T} J=+50^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)


## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators

## ELECTRICAL CHARACTERISTICS (continued)

 $\mathrm{T}_{J}=+75^{\circ} \mathrm{C}$. All temperature coefficients measured at $\mathrm{T} J=+50^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS |  | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| AC CHARACTERISTICS (Note 5) |  |  |  |  |  |  |  |
| Dynamic Output Current |  | (Note 1) |  | 40 |  |  | mA |
| Drive-Mode Overshoot, Undershoot, and Preshoot |  | 200 mV to 4VP-P swing (Note 6) |  | $\begin{gathered} 5 \% \\ +10 \end{gathered}$ |  |  | mV |
| Term-Mode Spike |  | $\mathrm{V}_{\text {DHV }}=\mathrm{V}_{\text {DTV }}=1 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0 \mathrm{~V}$ |  | 25 |  |  | mV |
|  |  | $\mathrm{V}_{\text {DLV }}=\mathrm{V}_{\text {DTV }}=0 \mathrm{~V}, \mathrm{~V}_{\text {DHV }}=1 \mathrm{~V}$ |  | 25 |  |  |  |
| High-Impedance-Mode Spike |  | $V_{D L V}=-1 \mathrm{~V}, \mathrm{~V}_{\text {DHV }}=0 \mathrm{~V}$ |  | 25 |  |  | mV |
|  |  | $\mathrm{V}_{\text {DLV }}=0 \mathrm{~V}, \mathrm{~V}_{\text {DHV }}=1 \mathrm{~V}$ |  | 25 |  |  |  |
| Propagation Delay, Data to Output |  |  |  | 1.6 | 2.6 | 4.2 | ns |
| Prop-Delay Temperature Coefficient |  |  |  |  | 10 |  | ps/ ${ }^{\circ} \mathrm{C}$ |
| Prop-Delay Match, tLH vs. thL |  |  |  |  | 30 |  | ps |
| Prop-Delay Skew, Drivers Within Package |  |  |  |  | 150 |  | ps |
| Prop-Delay Change vs. Pulse Width |  | Relative to 12.5 ns pulse | $3 V_{P-P, ~ 40 M H z, ~}^{\text {, }}$ <br> $\mathrm{PW}=4 \mathrm{~ns}$ to 21 ns |  | 20 |  | ps |
|  |  |  | $\begin{aligned} & \text { 1VP-P, 40MHz, } \\ & \mathrm{PW}=2.5 \mathrm{~ns} \text { to } 23.5 \mathrm{~ns} \end{aligned}$ |  | 90 |  |  |
| Prop-Delay Change vs. CommonMode Voltage |  | $1 \mathrm{~V}_{\text {P-P, }} \mathrm{V}_{\text {DLV_ }}=0$ to 3 V , relative to delay at $V_{D L V}=1 \mathrm{~V}$ |  | 80 |  |  | ps |
| Prop Delay, Data to High Impedance |  | $\mathrm{V}_{\text {DHV }}=+1.5 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=-1.5 \mathrm{~V}$, both directions |  | 1.8 |  |  | ns |
| Prop Delay, Data to Term |  | $\mathrm{V}_{\text {DHV }}=+1.5 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=-1.5 \mathrm{~V}, \mathrm{~V}_{\text {DTV_ }}=0 \mathrm{~V},$ both directions |  | 1.6 |  |  | ns |
| Minimum Voltage Swing |  | (Note 7) |  | 25 |  |  | mV |
| Rise/Fall Time |  | $\mathrm{V}_{\text {DHV }}=0.2 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0 \mathrm{~V}, 20 \%$ to $80 \%$ |  | 0.7 |  |  | ns |
|  |  | $V_{\text {DHV }}=1 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0 \mathrm{~V}, 20 \%$ to $80 \%$ |  | 0.7 |  |  |  |
|  |  | $V_{D H V_{-}}=3 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0 \mathrm{~V}, 10 \% \text { to } 90 \%$ |  | 1.5 | 2.0 | 2.5 |  |
|  |  | $\begin{aligned} & V_{D H V}=4 V, V_{D L V}=0 V \\ & R_{L}=500-10 \% \text { to } 90 \% \end{aligned}$ |  | 2.6 |  |  |  |
|  |  | $\begin{aligned} & V_{D H V}=5 \mathrm{~V}, V_{\text {DLV }}=0 \mathrm{~V}, \\ & R_{L}=500-10 \% \text { to } 90 \% \end{aligned}$ |  | 3.4 |  |  |  |
| Rise/Fall-Time Matching |  | $\mathrm{V}_{\text {DHV }}=1 \mathrm{~V}$ to 5 V |  | $\pm 5$ |  |  | \% |
| Minimum Pulse Width (Note 8) |  | 200 mV , $\mathrm{V}_{\text {DHV }}=0.2 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0 \mathrm{~V}$ |  | 1.8 |  |  | ns |
|  |  | $1 \mathrm{~V}, \mathrm{~V}_{\text {DHV }}=1 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0 \mathrm{~V}$ |  | 2.4 |  |  |  |
|  |  | $3 \mathrm{~V}, \mathrm{~V}_{\text {DHV }}=3 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0 \mathrm{~V}$ |  | 3.3 |  |  |  |

## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators

## ELECTRICAL CHARACTERISTICS (continued)

 $\mathrm{T}_{J}=+75^{\circ} \mathrm{C}$. All temperature coefficients measured at $\mathrm{T}_{J}=+50^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| COMPARATOR (Note 9) |  |  |  |  |  |  |
| DC CHARACTERISTICS (driver in high-impedance mode) ( $\mathrm{V}_{\text {COMPHI }}=0.8 \mathrm{~V}, \mathrm{~V}_{\text {complo }}=0.2 \mathrm{~V}$ ) |  |  |  |  |  |  |
| Input Voltage Range |  |  | -2.2 |  | +5.2 | V |
| Differential Input Voltage |  | $\mathrm{V}_{\text {DUT_ }}-\mathrm{V}_{\text {CHV_ }}, \mathrm{V}_{\text {DUT_ }}$ - $\mathrm{V}_{\text {CLV }}$ | -7.4 |  | +7.4 | V |
| Hysteresis |  | $\mathrm{V}_{C H V_{-}}=\mathrm{V}_{\mathrm{CLV}_{-}}=1.5 \mathrm{~V}$ |  | 8 |  | mV |
| Input Offset Voltage |  | $\mathrm{V}_{\text {DUT }}=1.5 \mathrm{~V}$ |  |  | $\pm 10$ | mV |
| Input Offset Temperature Coefficient |  |  |  | 25 |  | $\mu \mathrm{V} /{ }^{\circ} \mathrm{C}$ |
| Common-Mode Rejection Ratio | CMRR | V $\mathrm{VUT}_{-}=0$ and 3 V | 60 |  |  | dB |
| Linearity Error (Note 10) |  | $\mathrm{V}_{\text {DUT }}=1.5 \mathrm{~V}$ |  |  | $\pm 5$ | mV |
|  |  | $\mathrm{V}_{\text {DUT_ }}=-2.2 \mathrm{~V},+5.2 \mathrm{~V}$ |  |  | $\pm 10$ |  |
| Power-Supply Rejection Ratio | PSRR | $V_{\text {DUT_ }}=1.5 \mathrm{~V}$, supplies independently varied over full range |  |  | 5 | $\mathrm{mV} / \mathrm{N}$ |
| AC CHARACTERISTICS (Note 11) |  |  |  |  |  |  |
| Equivalent Input Bandwidth |  | Terminated (Note 12) |  | 500 |  | MHz |
|  |  | High impedance (Note 13) |  | 300 |  |  |
| Propagation Delay |  |  | 0.9 | 2.2 | 3.1 | ns |
| Prop-Delay Temperature Coefficient |  |  |  | 4 |  | ps/ ${ }^{\circ} \mathrm{C}$ |
| Prop-Delay Match, tLH to thL |  |  |  | 120 |  | ps |
| Prop-Delay Skew, Comparators Within Package |  | Same edges (LH and HL) |  | 200 |  | ps |
| Prop-Delay Dispersions vs. Common-Mode Voltage (Note 14) |  | 0 to 4.9V |  | 20 |  | ps |
|  |  | -1.9 V to +4.9 V |  | 30 |  |  |
| Prop-Delay Dispersions vs. Overdrive |  | $\begin{aligned} & V_{C H V_{-}}=V_{C L V_{-}}=0.1 \mathrm{~V} \text { to } 0.9 \mathrm{~V}, \\ & V_{D U T-}=1 V_{P-P}, t_{R}=t_{F}=500 \mathrm{ps}, 10 \% \text { to } \\ & 90 \% \text { relative to timing at } 50 \% \text { point } \end{aligned}$ |  | 220 |  | ps |
| Prop-Delay Dispersions vs. Pulse Width |  | $2 n s$ to 23 ns pulse width, relative to 12.5 ns pulse width |  | $\pm 60$ |  | ps |
| Prop-Delay Dispersions vs. Slew Rate |  | $0.5 \mathrm{~V} / \mathrm{ns}$ to $2 \mathrm{~V} / \mathrm{ns}$ |  | 50 |  | ps |

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## ELECTRICAL CHARACTERISTICS (continued)

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| PARAMETER | SYMBOL | CONDITIONS |  | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| LOGIC OUTPUTS |  |  |  |  |  |  |  |
| Reference Voltages COMPHI and COMPLO |  | (Note 15) |  | 0 |  | +3.6 | V |
| Output High Voltage Offset |  | IOUT $=0 \mathrm{~mA}$, relative to COMPHI at $\mathrm{V}_{\mathrm{COMPHI}}=1 \mathrm{~V}$ |  |  |  | $\pm 50$ | mV |
| Output Low Voltage Offset |  | IOUT $=0 \mathrm{~mA}$, relative to COMPLO at VCOMPLO $=0 \mathrm{~V}$ |  |  |  | $\pm 50$ | mV |
| Output Resistance |  | $\mathrm{ICHV}_{-}=\mathrm{ICLV}_{-}= \pm 10 \mathrm{~mA}$ |  | 40 | 50 | 60 | $\Omega$ |
| Current Limit |  |  |  | 25 |  |  | mA |
| Rise/Fall Time |  | $\begin{aligned} & 20 \% \text { to } 80 \%, V_{C H V}=1 V_{P-P}, \\ & \text { load }=T-\text { line, } 50 \Omega,>1 \mathrm{~ns} \end{aligned}$ |  | 0.7 |  |  | ns |
| PASSIVE LOAD |  |  |  |  |  |  |  |
| DC CHARACTERISTICS (RDUT_ $\geq 10 \mathrm{M} \Omega$ ) |  |  |  |  |  |  |  |
| LDV_ Voltage Range |  |  |  | -2.2 |  | +5.2 | V |
| Gain |  |  |  | 0.99 |  | 1.01 | $\mathrm{V} / \mathrm{V}$ |
| Gain Temperature Coefficient |  |  |  |  | 0.02 |  | \%/ ${ }^{\circ} \mathrm{C}$ |
| Offset |  |  |  |  |  | $\pm 100$ | mV |
| Offset Temperature Coefficient |  |  |  |  | 0.02 |  | $\mathrm{mV} /{ }^{\circ} \mathrm{C}$ |
| Power-Supply Rejection Ratio | PSRR |  |  | 10 |  |  | mV/V |
| Output Resistance <br> Tolerance—High Value |  | $\mathrm{IDUT}_{-}= \pm 0.2 \mathrm{~mA}, \mathrm{~V}_{\text {LDV }}^{-}$= $=1.5 \mathrm{~V}$ |  | 7.125 | 7.5 | 7.875 | k $\Omega$ |
| Output Resistance Tolerance-Low Value |  | $\mathrm{I}_{\text {DUT_ }}= \pm 0.1 \mathrm{~mA}, \mathrm{~V}_{\text {LDV }}$ - $=1.5 \mathrm{~V}$ |  | 1.90 | 2.0 | 2.10 | k $\Omega$ |
| Switch Resistance Variation |  | Relative to 1.5 V | 0 to 3V |  | $\pm 10$ |  | \% |
|  |  |  | Full range |  | $\pm 30$ |  |  |
| Maximum Output Current (Note 16) |  | $\mathrm{V}_{\text {LDV_- }}=-2 \mathrm{~V}, \mathrm{~V}_{\text {DUT_- }}=+5 \mathrm{~V}$ |  |  | $\pm 4$ |  | mA |
|  |  | $\mathrm{V}_{\text {LDV__ }}=+5 \mathrm{~V}, \mathrm{~V}_{\text {DUT_ }}=-2 \mathrm{~V}$ |  |  | $\pm 4$ |  |  |
| Linearity Error, Full Range |  | Measured at $-2.2 \mathrm{~V},+1.5 \mathrm{~V}$, and +5.2 V (Note 16) |  |  |  | $\pm 25$ | mV |
| AC CHARACTERISTICS |  |  |  |  |  |  |  |
| Settling Time, LDV_ to Output |  | $V_{\text {LDV }}^{-}=-2 \mathrm{~V}$ to +5 V step, RDUT_ $=100 \mathrm{k} \Omega$ (Note 17) |  |  | 0.5 |  | $\mu \mathrm{s}$ |
| Output Transient Response |  | $\begin{aligned} & \mathrm{V}_{\text {LDV_ }}^{-}=+1.5 \mathrm{~V}, \mathrm{~V}_{\text {DUT_ }}=-2 \mathrm{~V} \text { to }+5 \mathrm{~V} \text { square } \\ & \text { wave at } 1 \mathrm{MHz}, \text { RDUT_ }=50 \Omega \end{aligned}$ |  |  | 20 |  | ns |

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## ELECTRICAL CHARACTERISTICS (continued)

 $\mathrm{T}_{J}=+75^{\circ} \mathrm{C}$. All temperature coefficients measured at $\mathrm{T} J=+50^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| PMU SWITCHES (FORCE_, SENSE_, PMU_) |  |  |  |  |  |  |
| Voltage Range |  |  | -2.2 |  | +5.2 | V |
| Force Switch Resistance |  | $\mathrm{V}_{\text {FORCE }}=1.5 \mathrm{~V}$, IPMU_ $= \pm 10 \mathrm{~mA}$ |  |  | 40 | $\Omega$ |
| Force Switch Compliance |  | $\mathrm{V}_{\text {PMU_ }}=6.2 \mathrm{~V}, \mathrm{~V}_{\text {FORCE }}$ set to make $\mathrm{I}_{\text {FORCE }}=30 \mathrm{~mA}$ | 25 |  |  | mA |
|  |  | $V_{\text {PMU_ }}=-3.2 \mathrm{~V}$, $\mathrm{V}_{\text {FORCE_ }}$ set to make ${ }^{\text {IFORCE_ }}=-30 \mathrm{~mA}$ | 25 |  |  |  |
| Force Switch Resistance Variation (Note 18) |  | 0 to 3V | $\pm 10$ |  |  | \% |
|  |  | Full range | $\pm 30$ |  |  |  |
| Sense Switch Resistance |  |  | 700 | 1000 | 1300 | $\Omega$ |
| Sense Switch Resistance Variation |  | Relative to 1.3 V , full range | $\pm 30$ |  |  | \% |
| PMU_Capacitance |  | Force-and-sense switches open | 5 |  |  | pF |
| FORCE_ Capacitance |  |  | 5 |  |  | pF |
| SENSE_Capacitance |  |  | 0.2 |  |  | pF |
| FORCE_ External Capacitance |  | Allowable external capacitance | 2 |  |  | nF |
| SENSE_External Capacitance |  | Allowable external capacitance | 1 |  |  | nF |
| FORCE_ and SENSE_ Switching Speed |  | Connect or disconnect | 10 |  |  | $\mu \mathrm{s}$ |
| PMU_ Leakage |  | $\begin{array}{\|l} \text { FORCE EN_ }=\text { SENSE EN } \text { S }_{-}=0, \\ \text { VFORCE }_{-}=\text {V SENSE }_{-}=-2.2 \mathrm{~V} \text { to }+5.2 \mathrm{~V} \end{array}$ |  | $\pm 0.5$ | $\pm 5$ | nA |
| TOTAL FUNCTION |  |  |  |  |  |  |
| DUT |  |  |  |  |  |  |
| Leakage, High-Impedance Mode |  | Load switches open, $\begin{aligned} & \mathrm{V}_{\text {DUT_ }}=+5.2 \mathrm{~V}, \\ & \mathrm{~V}_{\text {CLV }}=\mathrm{V}_{\text {CHV }}=-2.2 \mathrm{~V}, \\ & \mathrm{~V}_{\text {DUT_ }}=-2.2 \mathrm{~V}, \\ & \mathrm{~V}_{\text {CLV }}=\mathrm{V}_{\text {CHV }}=+5.2 \mathrm{~V}, \text { full range } \\ & \hline \end{aligned}$ |  | 2 |  | $\mu \mathrm{A}$ |
| Leakage, Low-Leakage Mode |  | Full range |  | $\pm 1$ | $\pm 20$ | nA |
| Low-Leakage Recovery Time |  | (Note 19) |  | 10 |  | $\mu \mathrm{s}$ |
| Combined Capacitance |  | Term mode | 5 |  |  | pF |
|  |  | High-impedance mode |  |  |  |  |
| Load Resistance |  | (Note 20) | 1 |  |  | G $\Omega$ |
| Load Capacitance |  | (Note 20) | 12 |  |  | nF |

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## ELECTRICAL CHARACTERISTICS (continued)

 $\mathrm{T}_{J}=+75^{\circ} \mathrm{C}$. All temperature coefficients measured at $\mathrm{T} J=+50^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| VOLTAGE REFERENCE INPUTS (DHV_, DTV_, DLV_, DATA_, RCV_, CHV_, CLV_, LDV_, COMPHI, COMPLO) |  |  |  |  |  |  |
| Input Bias Current |  |  |  |  | $\pm 100$ | $\mu \mathrm{A}$ |
| Input Bias Current Temperature Coefficient |  |  |  | $\pm 200$ |  | $n \mathrm{n} /{ }^{\circ} \mathrm{C}$ |
| Settling to Output |  | 0.1\% of full-scale step |  | 10 |  | $\mu \mathrm{s}$ |
| DIGITAL INPUTS (DATA_, RCV , $\overline{\text { LD }}$, DIN, SCLK, $\overline{\text { CS }}$ ) |  |  |  |  |  |  |
| Input High Voltage |  | (Note 21) | $\begin{gathered} \mathrm{V}_{\mathrm{L}} / 2+ \\ 0.2 \end{gathered}$ |  | +3.6 | V |
| Input Low Voltage |  | (Note 21) | 0 |  | $\begin{gathered} \text { VL/2 - } \\ 0.2 \end{gathered}$ | V |
| Input Bias Current | DATA, |  |  |  | 100 | $\mu \mathrm{A}$ |
|  | $\overline{\mathrm{LD}}, \mathrm{DIN}$, SCLK, $\overline{C S}$ |  |  |  | 1 |  |
| SERIAL DATA OUTPUT (DOUT) |  |  |  |  |  |  |
| Output High Voltage |  | $\mathrm{IOH}=-1 \mathrm{~mA}$ | $\begin{gathered} V_{L} \\ -0.4 \end{gathered}$ |  | VL | V |
| Output Low Voltage |  | $\mathrm{IOL}=1 \mathrm{~mA}$ | 0 |  | +0.4 | V |
| Output Rise and Fall Time |  | $C_{L}=10 \mathrm{pF}$ |  | 1.1 |  | ns |
| SERIAL-INTERFACE TIMING (Note 22) |  |  |  |  |  |  |
| SCLK Frequency |  |  |  |  | 50 | MHz |
| SCLK Pulse-Width High | tch |  | 10 |  |  | ns |
| SCLK Pulse-Width Low | tCL |  | 10 |  |  | ns |
| $\overline{\mathrm{CS}}$ Low to SCLK High Setup | tcsso |  | 3.5 |  |  | ns |
| SCLK High to $\overline{\mathrm{CS}}$ Low Hold | tCSHO |  | 3.5 |  |  | ns |
| $\overline{\mathrm{CS}}$ High to SCLK High Setup | tCSS1 |  | 3.5 |  |  | ns |
| SCLK High to $\overline{\mathrm{CS}}$ High Hold | tCSH1 |  | 15 |  |  | ns |
| DIN to SCLK High Setup | tDS |  | 7.5 |  |  | ns |
| DIN to SCLK High Hold | tDH |  | 3.5 |  |  | ns |
| $\overline{\mathrm{CS}}$ High to $\overline{\text { LOAD Low Hold }}$ | tCSHLD |  | 6 |  |  | ns |
| $\overline{\mathrm{CS}}$ High Pulse Width | tcswh |  | 20 |  |  | ns |
| $\overline{\text { LD Low Pulse Width }}$ | tLDW |  | 20 |  |  | ns |
| $\overline{\mathrm{LD}}$ High to Any Activity |  |  | 0 |  |  | ns |
| SCLK Low to DOUT Delay | tDo | $C \mathrm{~L}=10 \mathrm{pF}$ | 5 |  | 40 | ns |
| $V_{\text {L }}$ Rising to $\overline{\mathrm{CS}}$ Low |  | Power-on delay |  | 2 |  | $\mu \mathrm{s}$ |
| TEMP SENSOR |  |  |  |  |  |  |
| Nominal Voltage |  | $\mathrm{T}_{\mathrm{J}}=+27^{\circ} \mathrm{C}$ |  | 3.20 |  | V |
| Temperature Coefficient |  |  |  | +10 |  | $\mathrm{mV} /{ }^{\circ} \mathrm{C}$ |
| Output Resistance |  |  |  | 500 |  | $\Omega$ |

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## ELECTRICAL CHARACTERISTICS (continued)

 $\mathrm{TJ}=+75^{\circ} \mathrm{C}$. All temperature coefficients measured at $\mathrm{T} J=+50^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| POWER SUPPLIES |  |  |  |  |  |  |
| Positive Supply Voltage | VDD | (Note 23) | 7.6 | 8 | 8.4 | V |
| Negative Supply Voltage | $V_{S S}$ | (Note 23) | -5.25 | -5 | -4.75 | V |
| Logic Supply Voltage | VL |  | 2.3 |  | 3.6 | V |
| Positive Supply Current | IDD | fout $=0 \mathrm{MHz}$ |  | 97 | 120 | mA |
| Negative Supply Current | ISS | fout $=0 \mathrm{MHz}$ |  | 99 | 120 | mA |
| Logic Supply Current | IL |  |  | 0.15 | 0.30 | mA |
| Static Power Dissipation |  | fout $=0 \mathrm{MHz}$ |  | 1.3 | 1.5 | W |
| Operating Power Dissipation |  | fout $=100 \mathrm{Mbps}$ (Note 24) |  | 1.4 |  | W |

Note 1: All minimum and maximum specifications are 100\% production tested except driver dynamic output current and driver/comparator propagation delays, which are guaranteed by design. All specifications are with DUT_ and PMU_ electrically isolated, unless otherwise noted.
Note 2: Nominal target value is $49.5 \Omega$. Contact factory for alternate trim selections within the $45 \Omega$ to $55 \Omega$ range.
Note 3: Measured at 1.5 V , relative to a straight line through 0 and 3 V .
Note 4: Measured at end points, relative to a straight line through 0 and $3 V$.
Note 5: DUT_ is terminated with $50 \Omega$ to ground, $V_{D H V}=3 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0, \mathrm{~V}_{\text {DTV }}=1.5 \mathrm{~V}$, unless otherwise specified. DATA_ and RCV_ logic levels are $\mathrm{V}_{\text {HIGH }}=2 \mathrm{~V}, \mathrm{~V}_{\text {LOW }}=1 \mathrm{~V}$.
Note 6: Undershoot is any reflection of the signal back towards its starting voltage after it has reached $90 \%$ of its swing. Preshoot is any aberration in the signal before it reaches $10 \%$ of its swing.
Note 7: At the minimum voltage swing, undershoot is less than $20 \%$. DHV_ and DLV_ references are adjusted to result in the specified swing.
Note 8: At this pulse width, the output reaches at least $90 \%$ of its nominal (DC) amplitude. The pulse width is measured at DATA_.
Note 9: With the exception of offset and gain/CMRR tests, reference input values are calibrated for offset and gain.
Note 10: Relative to a straight line through 0 and 3 V .
Note 11: Unless otherwise noted, all propagation delays are measured at $40 \mathrm{MHz}, \mathrm{V}_{D_{U T}}=0$ to $1 \mathrm{~V}, \mathrm{~V}_{C H V}=\mathrm{V}_{C L V}=+0.5 \mathrm{~V}$, $\mathrm{tR}_{\mathrm{R}}=\mathrm{tF}_{\mathrm{F}}$ $=500 \mathrm{ps}, Z_{S}=50 \Omega$, driver in term mode with $\mathrm{V}_{\text {DTV }}=+0.5 \mathrm{~V}$. Comparator outputs are terminated with $50 \bar{\Omega}$ to GND.
Measured from VDUT_ crossing calibrated CHV_/CLV_ threshold to midpoint of nominal comparator output swing.
Note 12: Terminated is defined as driver in drive mode and set to zero volts.
Note 13: High impedance is defined as driver in high-impedance mode.
Note 14: V DUT_ $_{-}=200 \mathrm{mV}$ P-P. Propagation delay is compared to a reference time at 1.5 V .
Note 15: The comparator meets all its timing specifications with the specified output conditions when the output current is less than $10 \mathrm{~mA}, \mathrm{~V}_{\mathrm{COM}} \mathrm{MPHI}>\mathrm{V}_{\mathrm{COMPLO}}$, and $\mathrm{V}_{\mathrm{COMPH}}-\mathrm{V}_{\text {COMPLO}} \leq 1 \mathrm{~V}$. Higher voltage swings are valid but AC performance may degrade. The maximum comparator output swing is (COMPHI - COMPLO) $\leq 1 \mathrm{~V}$ when the output is terminated with a $50 \Omega$ resistor to termination voltage $\mathrm{V}_{\text {TERM }}$, where $\mathrm{COMPHI} \geq \mathrm{V}_{\text {TERM }} \geq$ COMPLO.
Note 16: LOAD EN LOW = LOAD EN HIGH = 1 .
Note 17: Waveform settles to within $5 \%$ of final value into load $100 \mathrm{k} \Omega$.
Note 18: IPMU_ $= \pm 2 \mathrm{~mA}$ at $\mathrm{V}_{\text {FORCE }}=-2.2 \mathrm{~V},+1.5 \mathrm{~V}$, and +5.2 V . Percent variation relative to value calculated at $\mathrm{V}_{\text {FORCE }}=+1.5 \mathrm{~V}$.
Note 19: Time to return to the specified maximum leakage after a $3 \mathrm{~V}, 4 \mathrm{~V} / \mathrm{ns}$ step at DUT_.
Note 20: Load at end of 2ns transmission line; for stability only, AC performance may be degraded.
Note 21: The driver meets all of its timing specifications over the specified digital input voltage range.
Note 22: Timing characteristics with VL = 3V.
Note 23: Specifications are simulated and characterized over the full power-supply range. Production tests are performed with power supplies at typical values.
Note 24: All channels driven at $3 V_{P-p}$, load $=2 n s, 50 \Omega$ transmission line terminated with $3 p F$.

# Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators 

( $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)


## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators

Typical Operating Characteristics (continued)
( $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)


# Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators 

Typical Operating Characteristics (continued)
( $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)



COMPARATOR OFFSET
vs. COMMON-MODE VOLTAGE


CROSSTALK, DUT_ DRIVEN BY DTV_ WITH DHV_VARIED




CROSSTALK, DUT_DRIVEN BY DTV_ WITH DLV_VARIED


COMPARATOR RESPONSE TO 0 TO 3V SIGNAL


COMPARATOR TIMING VARIATION vs. PULSE WIDTH


## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators



$\mathrm{t}=2.5 \mu \mathrm{~s} / \mathrm{div}$


Typical Operating Characteristics (continued)


LOW LEAKAGE TO DRIVE 1V TRANSITION

$t=100 \mathrm{~ns} /$ div


COMPARATOR OFFSET
vs. TEMPERATURE


HIGH-IMPEDANCE LEAKAGE AT DUT_
vs. DUT_VOLTAGE



# Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators 

Typical Operating Characteristics (continued)
( $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)


PMU_FORCE_SWITCH RESISTANCE vs. FORCE_CURRENT


PASSIVE LOAD HIGH RESISTOR vs. VOLTAGE


PMU_FORCE_SWITCH RESISTANCE
vs. FORCE_CURRENT


PASSIVE LOAD LOW RESISTOR vs. VOLTAGE


PMU_FORCE_SWITCH RESISTANCE vs. FORCE_CURRENT


# Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators 

Pin Description

| PIN | NAME | FUNCTION |
| :---: | :---: | :---: |
| 1 | DATA1 | Channel 1 Multiplexer Control Input. Selects driver 1 input from DHV1 or DLV1 in drive mode. See Table 1 and Figure 2. |
| 2 | RCV1 | Channel 1 Multiplexer Control Input. Sets channel 1 mode to drive or receive. See Table 1 and Figure 2. |
| $\begin{gathered} 3,8,13 \\ 18,51 \end{gathered}$ | GND | Analog Ground |
| 4 | CMPH1 | Channel 1 High-Side Comparator Output |
| 5 | CMPL1 | Channel 1 Low-Side Comparator Output |
| 6 | DATA2 | Channel 2 Multiplexer Control Input. Selects driver 2 input from DHV2 or DLV2 in drive mode. See Table 1 and Figure 2. |
| 7 | RCV2 | Channel 2 Multiplexer Control Input. Sets channel 2 mode to drive or receive. See Table 1 and Figure 2. |
| 9 | CMPH2 | Channel 2 High-Side Comparator Output |
| 10 | CMPL2 | Channel 2 Low-Side Comparator Output |
| 11 | CMPL3 | Channel 3 Low-Side Comparator Output |
| 12 | CMPH3 | Channel 3 High-Side Comparator Output |
| 14 | RCV3 | Channel 3 Multiplexer Control Input. Sets channel 3 mode to drive or receive. See Table 1 and Figure 2. |
| 15 | DATA3 | Channel 3 Multiplexer Control Input. Selects driver 3 input from DHV3 or DLV3 in drive mode. See Table 1 and Figure 2. |
| 16 | CMPL4 | Channel 4 Low-Side Comparator Output |
| 17 | CMPH4 | Channel 4 High-Side Comparator Output |
| 19 | RCV4 | Channel 4 Multiplexer Control Input. Sets channel 4 mode to drive or receive. See Table 1 and Figure 2. |
| 20 | DATA4 | Channel 4 Multiplexer Control Input. Selects driver 4 input from DHV4 or DLV4 in drive mode. See Table 1 and Figure 2. |
| 21 | DHV4 | Channel 4 Driver High Voltage Input |
| 22 | DLV4 | Channel 4 Driver Low Voltage Input |
| 23 | DTV4 | Channel 4 Driver Termination Voltage Input |
| 24 | CHV4 | Channel 4 Threshold Voltage Input for High-Side Comparator |
| 25 | CLV4 | Channel 4 Threshold Voltage Input for Low-Side Comparator |
| 26 | DHV3 | Channel 3 Driver High Voltage Input |
| 27 | DLV3 | Channel 3 Driver Low Voltage Input |
| 28 | DTV3 | Channel 3 Driver Termination Voltage Input |
| 29 | CHV3 | Channel 3 Threshold Voltage Input for High-Side Comparator |
| 30 | CLV3 | Channel 3 Threshold Voltage Input for Low-Side Comparator |
| 31 | DGND | Digital Ground Connection |
| 32 | DOUT | Serial-Interface Data Output |
| 33 | $\overline{\mathrm{LD}}$ | Load Input. Latches data from the serial input register to the control register on rising edge. Transparent when low. |
| 34 | DIN | Serial-Interface Data Input |
| 35 | SCLK | Serial Clock |
| 36 | $\overline{\mathrm{CS}}$ | Chip Select |
| 37 | SENSE4 | Channel 4 PMU Sense Connection |
| 38 | FORCE4 | Channel 4 PMU Force Connection |

# Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators 

Pin Description (continued)

| PIN | NAME | FUNCTION |
| :---: | :---: | :---: |
| 39 | SENSE3 | Channel 3 PMU Sense Connection |
| 40 | FORCE3 | Channel 3 PMU Force Connection |
| 41 | TEMP | Temperature Sensor Output |
| $\begin{gathered} 42,47,52, \\ 56,60 \end{gathered}$ | $V_{D D}$ | Positive Power-Supply Input |
| 43 | DUT4 | Channel 4 Device-Under-Test Connection. Driver, comparator, and load I/O node for channel 4. |
| 44 | PMU4 | Channel 4 Parametric Measurement Connection. PMU switch I/O node for channel 4. |
| $\begin{gathered} 45,50,53, \\ 57 \end{gathered}$ | VSS | Negative Power-Supply Input |
| 46 | VL | Logic Power-Supply Input |
| 48 | DUT3 | Channel 3 Device-Under-Test Connection. Driver, comparator, and load I/O node for channel 3. |
| 49 | PMU3 | Channel 3 Parametric Measurement Connection. PMU switch I/O node for channel 3. |
| 54 | PMU2 | Channel 2 Parametric Measurement Connection. PMU switch I/O node for channel 2. |
| 55 | DUT2 | Channel 2 Device-Under-Test Connection. Driver, comparator, and load I/O node for channel 2. |
| 58 | PMU1 | Channel 1 Parametric Measurement Connection. PMU switch I/O node for channel 1. |
| 59 | DUT1 | Channel 1 Device-Under-Test Connection. Driver, comparator, and load I/O node for channel 1. |
| 61 | FORCE2 | Channel 2 PMU Force Connection |
| 62 | SENSE2 | Channel 2 PMU Sense Connection |
| 63 | FORCE1 | Channel 1 PMU Force Connection |
| 64 | SENSE1 | Channel 1 PMU Sense Connection |
| 65 | COMPLO | Comparator Output-Low Voltage Reference Input |
| 66 | COMPHI | Comparator Output-High Voltage Reference Input |
| 67 | LDV4 | Channel 4 Load Voltage Input |
| 68 | LDV3 | Channel 3 Load Voltage Input |
| 69 | LDV2 | Channel 2 Load Voltage Input |
| 70 | LDV1 | Channel 1 Load Voltage Input |
| 71 | CLV2 | Channel 2 Threshold Voltage Input for Low-Side Comparator |
| 72 | CHV2 | Channel 2 Threshold Voltage Input for High-Side Comparator |
| 73 | DTV2 | Channel 2 Driver Termination Voltage Input |
| 74 | DLV2 | Channel 2 Driver Low Voltage Input |
| 75 | DHV2 | Channel 2 Driver High Voltage Input |
| 76 | CLV1 | Channel 1 Threshold Voltage Input for Low-Side Comparator |
| 77 | CHV1 | Channel 1 Threshold Voltage Input for High-Side Comparator |
| 78 | DTV1 | Channel 1 Driver Termination Voltage Input |
| 79 | DLV1 | Channel 1 Driver Low Voltage Input |
| 80 | DHV1 | Channel 1 Driver High Voltage Input |
| - | EP | Exposed Pad. Leave unconnected or connect to ground. |

## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators



Figure 1. Block Diagram

# Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators 

## Detailed Description

The MAX9972 is a four-channel, pin-electronics IC for automated test equipment that includes, for each channel, a three-level pin driver, a window comparator, a passive load, and a Kelvin instrument connection (Figure 1). All functions feature a -2.2 V to +5.2 V operating range and the drivers include both high-impedance and active-termination (3rd-level drive) modes. The comparators feature programmable output voltages, allowing optimization for different CMOS interface standards. The loads have selectable output resistance for optimizing DUT current loading. The Kelvin paths allow accurate connection of an instrument with $\pm 25 \mathrm{~mA}$ source/sink capability. Additionally, the MAX9972 offers a low-leakage mode that reduces DUT_ leakage current to less than 20nA.
Each of the four channels feature single-ended CMOScompatible inputs, DATA_ and RCV_, for control of the driver signal path (Figure 2). The MAX9972 modal operation is programmed through a 3-wire, low-voltage CMOS-compatible serial interface.

## Output Driver

The driver input is a high-speed multiplexer that selects one of three voltage inputs: $D H V_{-}$, DLV_, or DTV_. This switching is controlled by high-speed inputs DATA_ and RCV_, and mode-control bit TERM (Table 1). DATA_ and $\bar{R} C V_{-}$are single-ended inputs with threshold levels equal to $\bar{V} / / 2$. Each channel's threshold levels are independently generated to minimize crosstalk.
DUT_ can be toggled at high speed between the buffer output and high-impedance mode, or it can be placed into low-leakage mode (Figure 2, Table 1). High-speed input RCV_ and mode-control bits TERM and LLEAK control these modes. In high-impedance mode, the bias current at DUT_ is less than $2 \mu \mathrm{~A}$ over the -2.2 V to +5.2 V range, while the node maintains its ability to track high-speed signals. In low-leakage mode, the bias current at DUT_ is further reduced to less than 20nA, and signal tracking slows.

The nominal driver output resistance is $50 \Omega$. Custom resistance values from $45 \Omega$ to $51 \Omega$ are possible; consult factory for further information.

Table 1. Driver Channel Control Signals

| EXTERNAL CONNECTIONS |  | INTERNAL CONTROL BITS |  | DRIVER OUTPUT | DRIVER MODE |
| :---: | :---: | :---: | :---: | :---: | :---: |
| RCV_ | DATA | TERM | LLEAK |  |  |
| 0 | 0 | X | 0 | DUT_ = DLV_ | Drive |
| 0 | 1 | X | 0 | DUT_ = DHV_ | Drive |
| 1 | X | 0 | 0 | High Impedance | Receive |
| 1 | X | 1 | 0 | DUT_ = DTV_ | Receive |
| X | X | X | 1 | Low Leak | Low <br> Leakage |



Figure 2. Multiplexer and Driver Channel

# Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators 

## Comparators

The MAX9972 provides two independent high-speed comparators for each channel. Each comparator has one input connected internally to DUT_ and the other input connected to either $\mathrm{CHV}_{-}$or $\mathrm{CLV}_{-}$(see Figure 1). Comparator outputs are a logical result of the input conditions, as indicated in Table 2.
The comparator output voltages are easily interfaced to a wide variety of logic standards. Use buffered inputs COMPHI and COMPLO to set the high and low output voltages. For correct operation, COMPHI should be greater than or equal to COMPLO. The comparator $50 \Omega$ output impedance provides source termination (Figure 3).

Passive Load
The MAX9972 channels each feature a passive load consisting of a buffered input voltage, LDV_, connected to DUT_ through two resistive paths (Figure 1). Each path connects to DUT_ individually by a switch controlled through the serial interface. Programming options include none (load disconnected), either, or both paths connected. The loads facilitate fast open/short testing in conjunction with the comparator, and pullup of open-drain DUT_ outputs.

## Parametric Switches

Each of the four MAX9972 channels provides force-and-sense paths for connection of a PMU or other DC resource to the device-under-test (Figure 1). Each force-and-sense switch is independently controlled though the serial interface providing maximum application flexibility. PMU_ and DUT_ are provided on separate pins allowing designs that do not require the parametric switch feature to avoid the added capacitance of PMU_. It also allows PMU_ to connect to DUT_ either directly or with an impedance-matching network.

## Low-Leakage Mode, LLEAK

Asserting LLEAK through the serial port places the MAX9972 into a very-low-leakage state (see the Electrical Characteristics table). This mode is convenient for making IDDQ and PMU measurements without the need for an output disconnect relay. LLEAK control is independent for each channel.
When DUT_ is driven with a high-speed signal while LLEAK is asserted, the leakage current momentarily increases beyond the limits specified for normal operation. The low-leakage recovery specification in the Electrical Characteristics table indicates device behavior under this condition.

Table 2. Comparator Logic

| DUT_ $_{-}$> CHV_ | DUT_ $_{-}$> CLV | CMPH $_{-}$ | CMPL_ $_{-}$ |
| :---: | :---: | :---: | :---: |
| 0 | 0 | 0 | 0 |
| 0 | 1 | 0 | 1 |
| 1 | 0 | 1 | 0 |
| 1 | 1 | 1 | 1 |



Figure 3. Complementary 50 5 Comparator Outputs
Table 3. Passive Load Resistance Values

| HIGH RESISTOR (k $\Omega$ ) | LOW RESISTOR (k $\Omega$ ) |
| :---: | :---: |
| 7.5 | 2 |

Temperature Monitor
Each device supplies a single temperature output signal, TEMP, that asserts a nominal 3.43 V output voltage at a $+70^{\circ} \mathrm{C}(343 \mathrm{~K})$ die temperature. The output voltage increases proportionately with temperature at a rate of $10 \mathrm{mV} /{ }^{\circ} \mathrm{C}$. The temperature sensor output impedance is $500 \Omega$, typical.

## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators

## Serial Interface and Device Control

A CMOS-compatible serial interface controls the MAX9972 modes (Figure 4). Control data flow into a 12bit shift register (LSB first) and are latched when $\overline{\mathrm{CS}}$ is taken high. Data from the shift register are then loaded to the per-channel control latches as determined by bits D8-D11, and indicated in Figure 4 and Table 4.

The latches contain the six mode bits for each channel of the device. The mode bits, in conjunction with external inputs DATA_ and RCV_, manage the features of each channel. Transfer data asynchronously from the input registers to the channel registers by forcing $\overline{\mathrm{LD}}$ low. With $\overline{\mathrm{LD}}$ always low, data transfer on the rising edge of $\overline{\mathrm{CS}}$.


Figure 4. Serial Interface
Table 4. Control Register Bit Functions

| BIT | NAME | FUNCTION | PIT STATE <br> STATE |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | $\mathbf{0}$ | $\mathbf{1}$ | 0 |
| 0 | TERM | Term Mode Control | High Impedance | Term Mode | 0 |
| 1 | LLEAK | Assert Low-Leakage Mode | Term Mode | Low Leakage | 0 |
| 2 | SENSE EN | Enable Sense Switch | Disabled | Enabled | 0 |
| 3 | FORCE EN | Enable Force Switch | Disabled | Enabled | 0 |
| 4 | LOAD EN LOW | Enable Low Load Resistor | Disabled | Enabled | 0 |
| 5 | LOAD EN HIGH | Enable High Load Resistor | Disabled | Enabled | 0 |
| 6 | - | Unused | Unused | $X$ | $X$ |
| 7 | - | X | $\times$ | 0 |  |
| 8 | CH1 | Update Channel 1 Control Register | Disabled | Enabled | 1 |
| 9 | CH 2 | Update Channel 2 Control Register | Disabled | Enabled | 1 |
| 10 | CH 3 | Update Channel 3 Control Register | Disabled | Enabled | 1 |
| 11 | CH 4 | Update Channel 4 Control Register | Disabled | Enabled | 1 |

## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators



Figure 5. Serial-Interface Timing

## Heat Removal

With adequate airflow, no external heat sinking is needed under most operating conditions. If excess heat must be dissipated through the exposed pad, solder it to circuit board copper. The exposed pad must be either left unconnected, isolated, or connected to ground.

## Power Minimization

To minimize power consumption, activate only the needed channels. Each channel placed in low-leakage mode saves approximately 240 mW .

Chip Information
PROCESS: BiCMOS

## Package Information

For the latest package outline information and land patterns (footprints), go to www.maxim-ic.com/packages. Note that a "+", "\#", or "-" in the package code indicates RoHS status only. Package drawings may show a different suffix character, but the drawing pertains to the package regardless of RoHS status.

| PACKAGE <br> TYPE | PACKAGE <br> CODE | OUTLINE <br> NO. | LAND <br> PATTERN NO. |
| :---: | :---: | :---: | :---: |
| 80 TQFP-EP | $\mathrm{C} 80 \mathrm{E}+4$ | $\underline{\underline{21-0115}}$ | $\underline{\underline{90-0152}}$ |

## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators



## Quad, Ultra-Low-Power, 300Mbps ATE Drivers/Comparators

| REVISION NUMBER | REVISION DATE | DESCRIPTION | PAGES CHANGED |
| :---: | :---: | :---: | :---: |
| 0 | 6/06 | Initial release | - |
| 1 | 7/09 | Changed driver offset max value in Electrical Characteristics table and removed all references to MAX9971 | 1-22 |
| 2 | 4/10 | Added soldering temperature to Absolute Maximum Ratings, updated SCLK to DOUT specification in Electrical Characteristics table, and replaced Figure 5 | 2, 7, 20 |
| 3 | 9/10 | Updated Absolute Maximum Ratings and Figure 1 | 2, 16 |
| 4 | 12/10 | Updated Electrical Characteristics table and notes | 3, 4, 7, 8 |
| 5 | 1/11 | Changed maximum DC drive current in Electrical Characteristics table to reflect actual circuit operation | 2 |
| 6 | 3/11 | Narrowed down product offerings and modified exposed die pad connection description; added $\overline{\mathrm{CS}}$ high pulse width to Electrical Characteristics table | $\begin{gathered} 1,2,4,5,7,15 \\ 17,18,20 \end{gathered}$ |
| 7 | 6/11 | Corrected/changed SPI timing parameters to improve yield and changed global levels for $\mathrm{V}_{\mathrm{COMPH}}$ and $\mathrm{V}_{\text {COMPLO }}$ | 2-8 |
| 8 | 6/11 | Restored original global levels changed in Rev 7 | 2-8 |
| 9 | 10/11 | Correct value for Temp Sensor nominal voltage | 7 |

